

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination MAIER ET AL.	
		Examiner S. Devi, Ph.D.	Art Unit 1645	Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	Kim et al. Appl. Environ. Microbiol. 62: 1759-1763, 1996
V	Schlecht et al. Naturwissenschaften 80: 9-17, 1993, abstract
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
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